

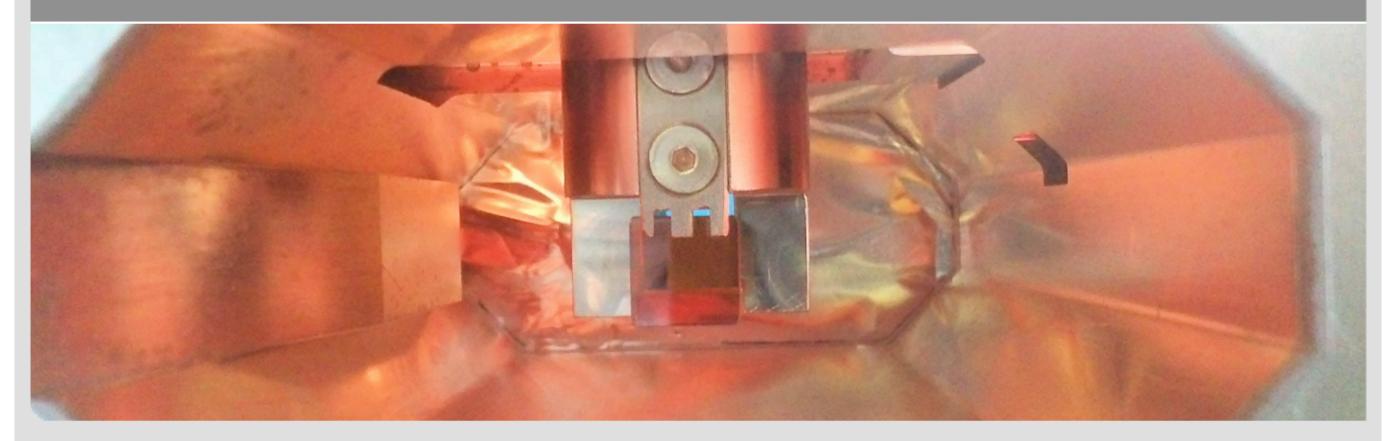




Electro-Optic Electron Bunch Diagnostic @ ANKA

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Outline

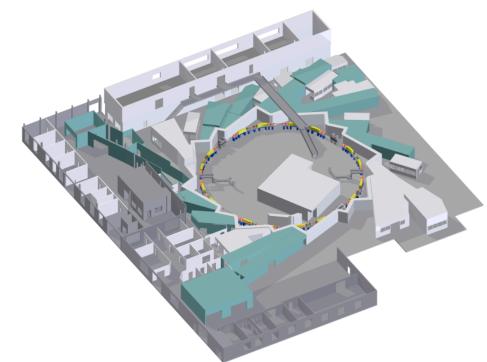


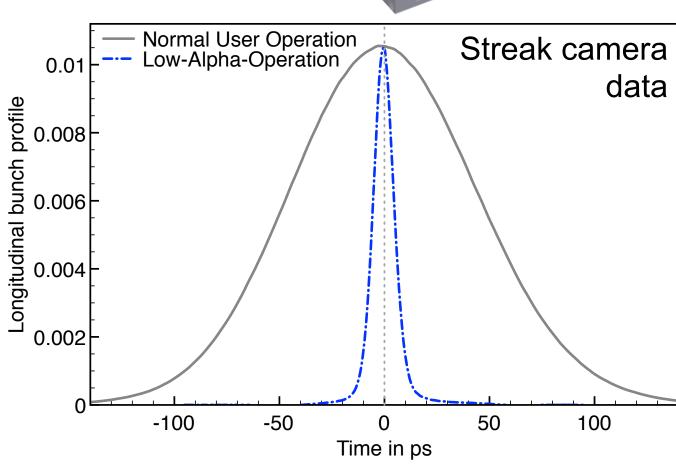
- Introduction: Low-α_c-Operation at ANKA
- Motivation for Single-Shot Bunch Profile Measurements
- Method:
 - Electro-Optic Sampling (EOS)
 - Electro-Optic Spectral Decoding (EOSD)
- Measurement results:
 - ■EOS: Long-Ranged Wake Field Studies
 - ■EOSD: Single-Shot Measurements

Introduction: Low-α_c-Operation at ANKA

Karlsruhe Institute of Technology

- Generation of coherent synchrotron radiation (CSR)
- Circumference 110.4 m
- \bullet f_{rev} = 2.715 MHz
- \bullet f_{RF} = 499.69 MHz
- Energy 0.5 2.5 GeV (0.8 1.6 GeV during low- $α_c$ -mode)
- RMS bunch length 45 ps (for 2.5 GeV), 10 ps down to 1-2 ps (for 1.3 GeV)
- Filling pattern: single- or multi-bunch (min. bunch spacing 2 ns)



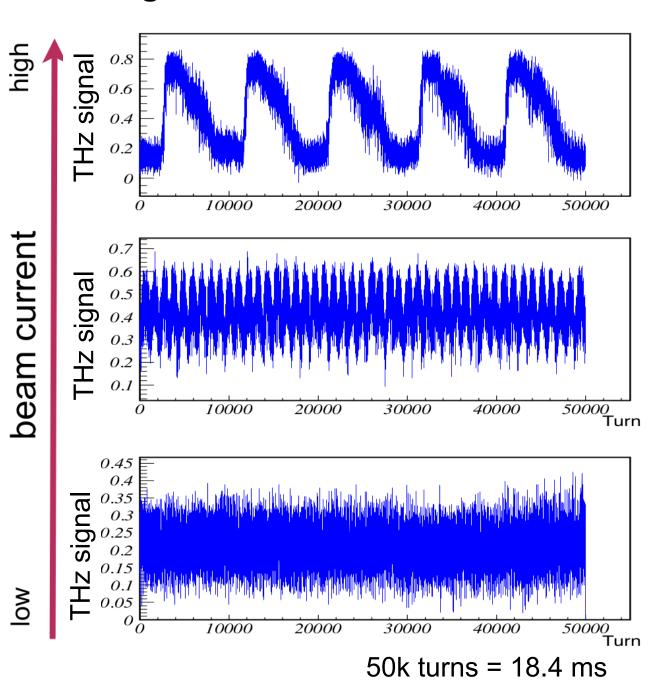


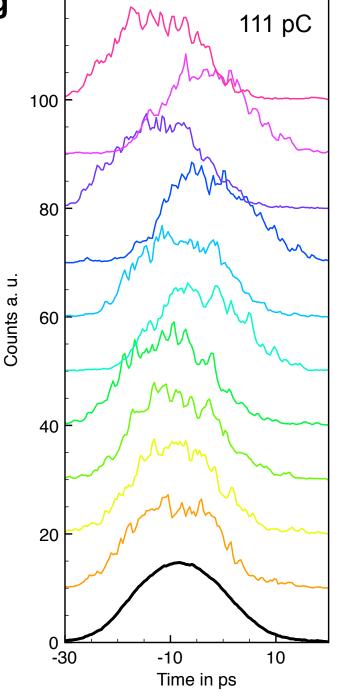
Motivation for single-shot EO measurements at ANKA

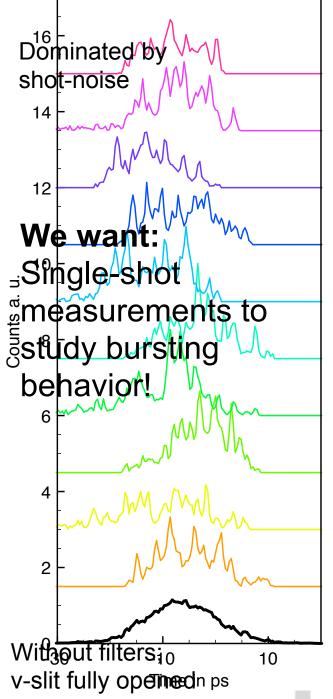


Streak Camera single-shot capabilities limited

Bursting behavior of CSR → microbunching



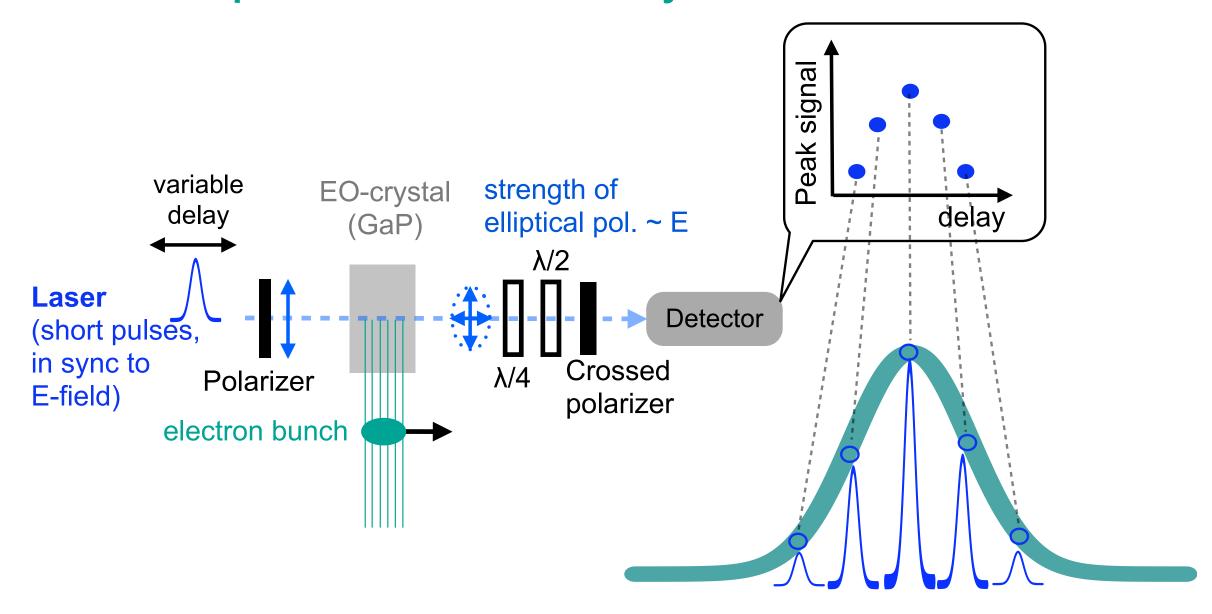




Electro-optical sampling (EOS)



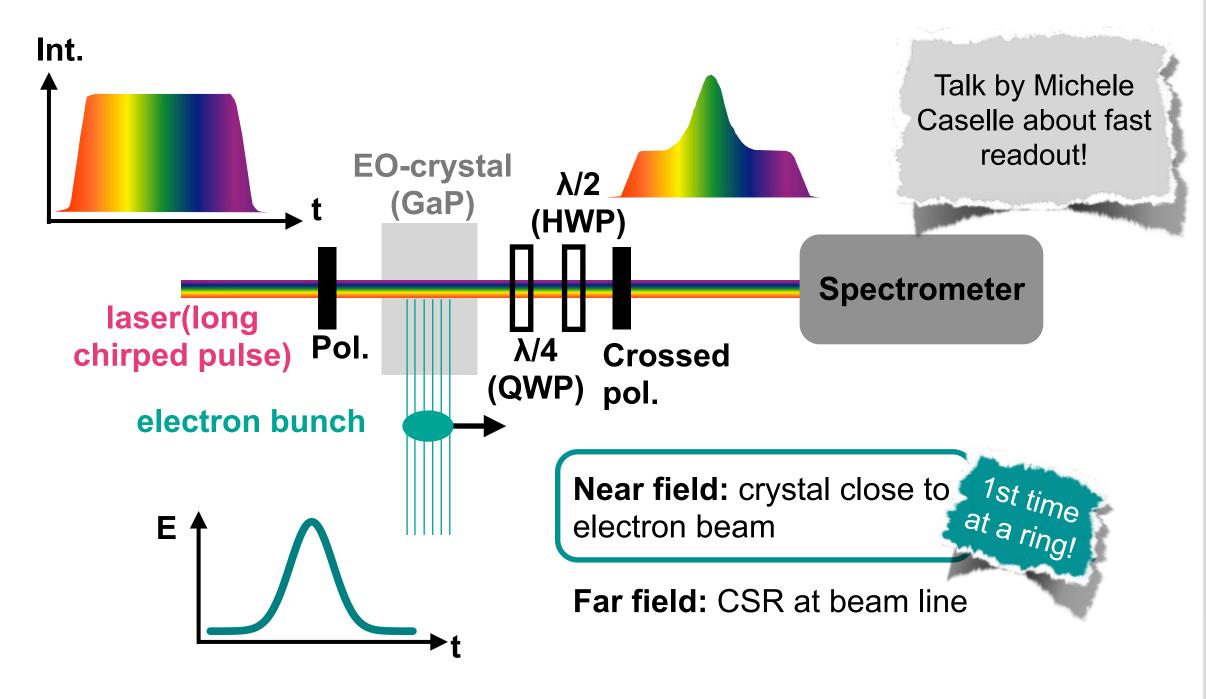
Intensity distribution of electron bunch is modulated onto laser pulse which is then analyzed.



best S/N ratio for nearly crossed polarizer and analyzer angles

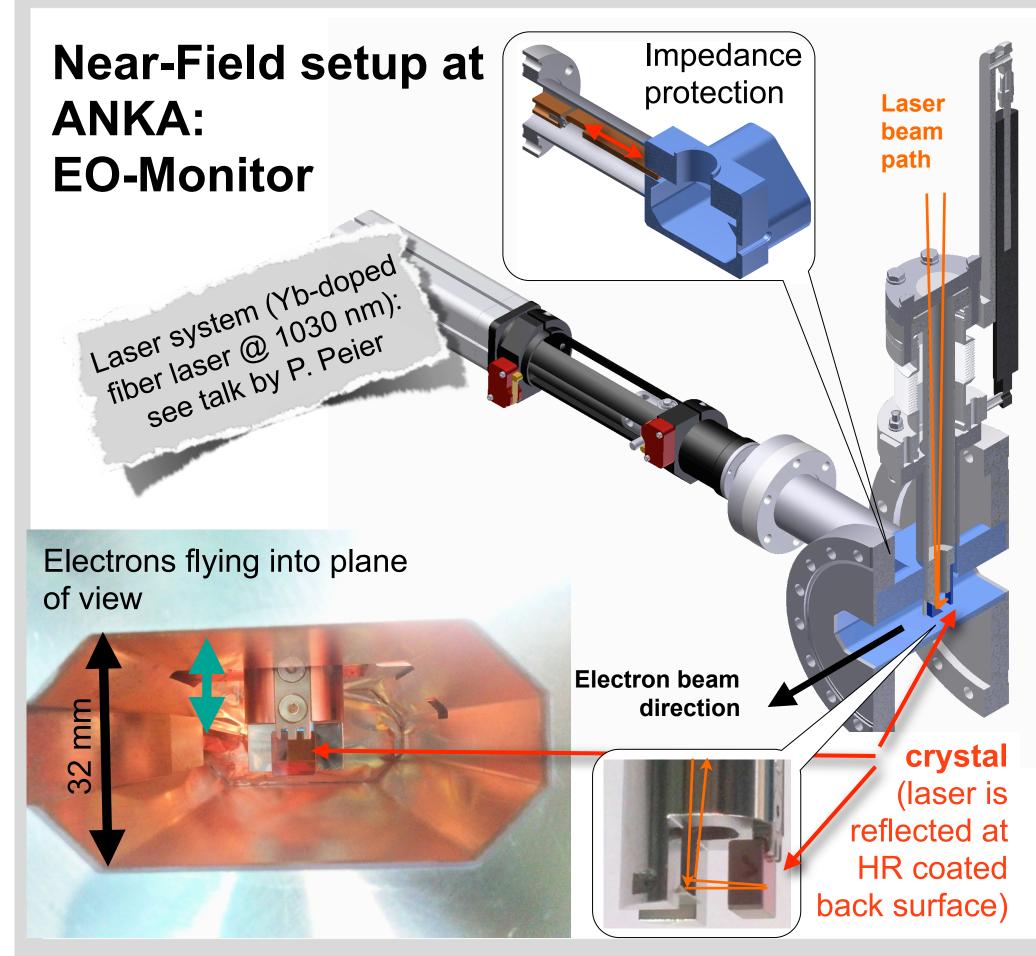
Spectral decoding (single shot) - EOSD





λ/4: compensate intrinsic birefringence of crystal

λ/2: control transmission through crossed polarizer



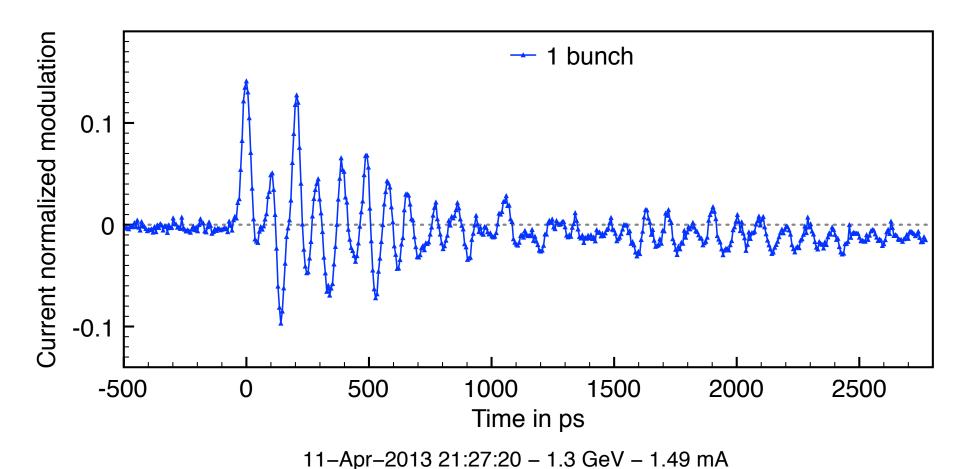


EO monitor with grating compressor and wave plates

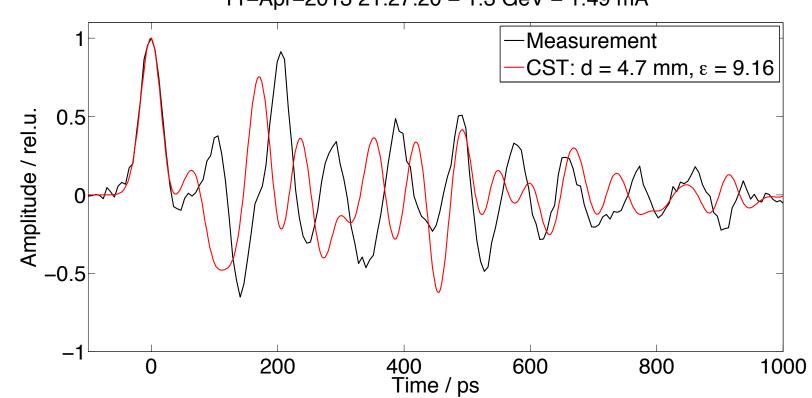


EOS: Long-Range Wake-Fields





Bunch spacing 2 ns

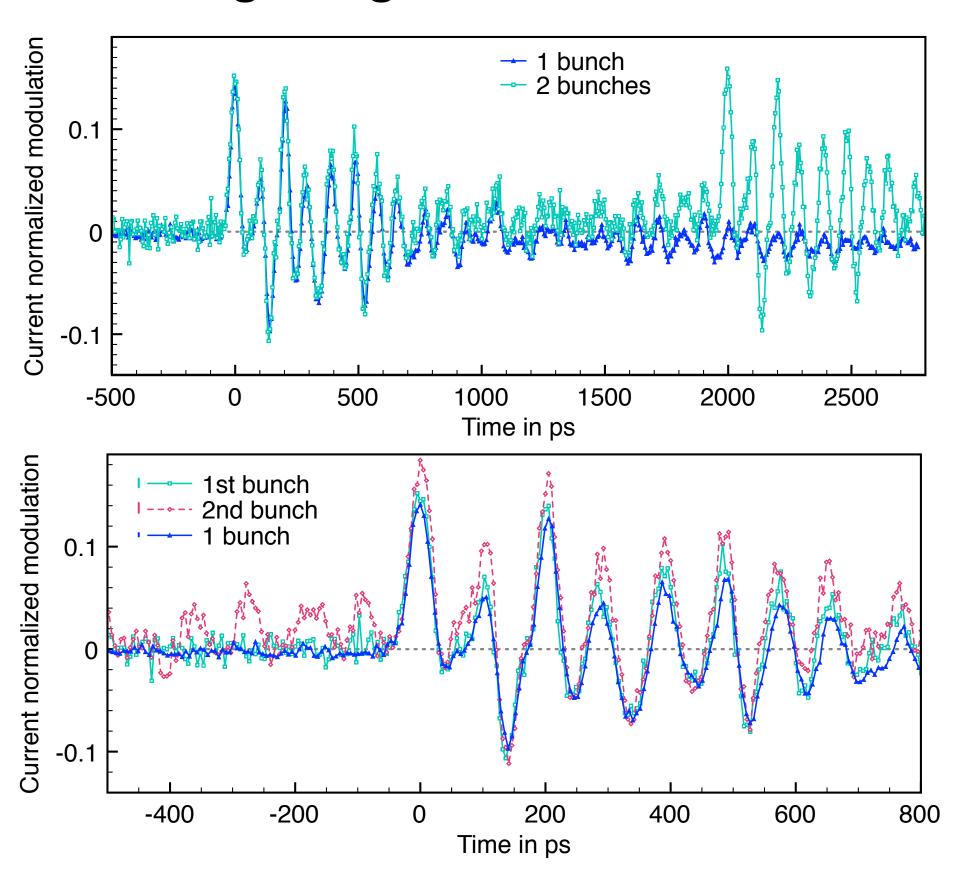


CST Simulations

B. Kehrer et al. Numerical Wakefield Calculations for Electro-optical Measurements, MOPME015, IPAC'13

EOS: Long-Range Wake-Fields



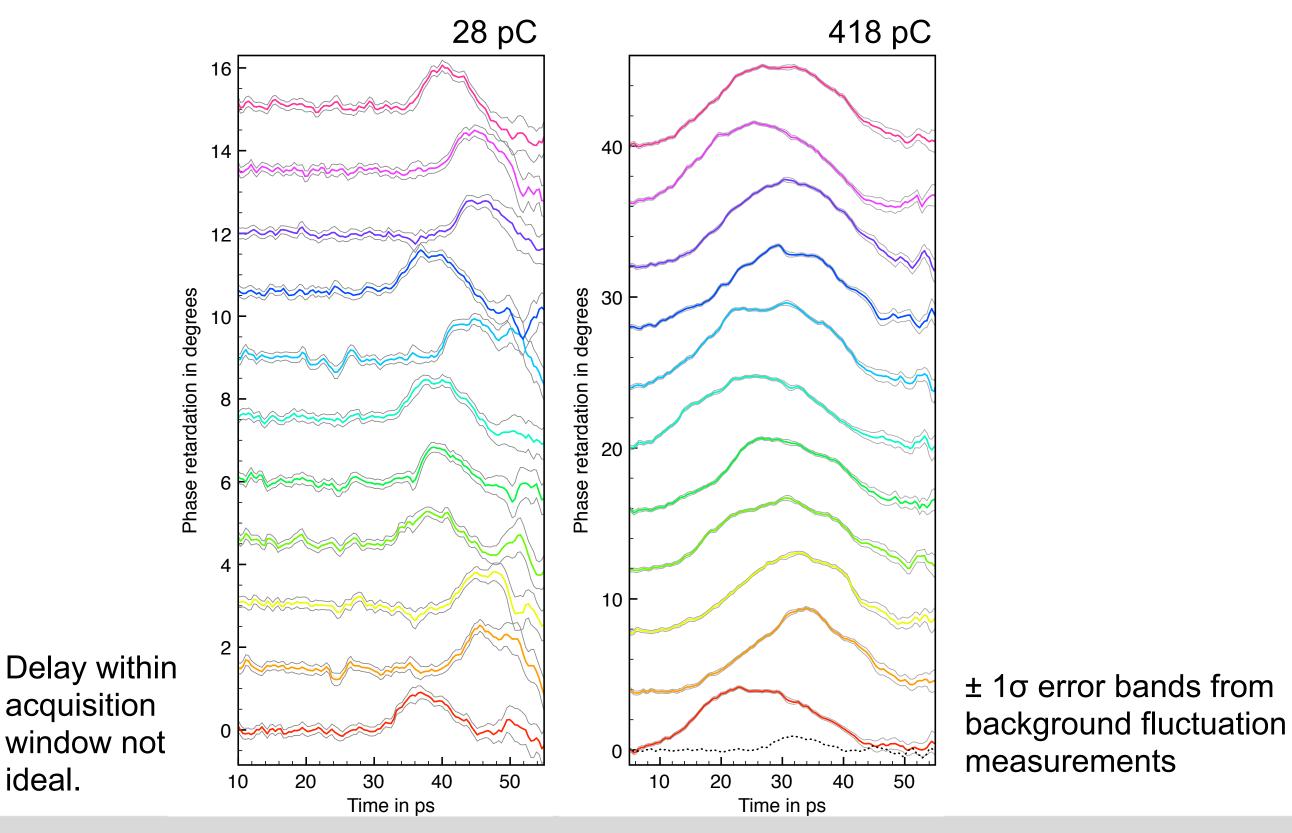


Bunch spacing 2 ns

Signal of 2nd bunch higher due to wake-fields!

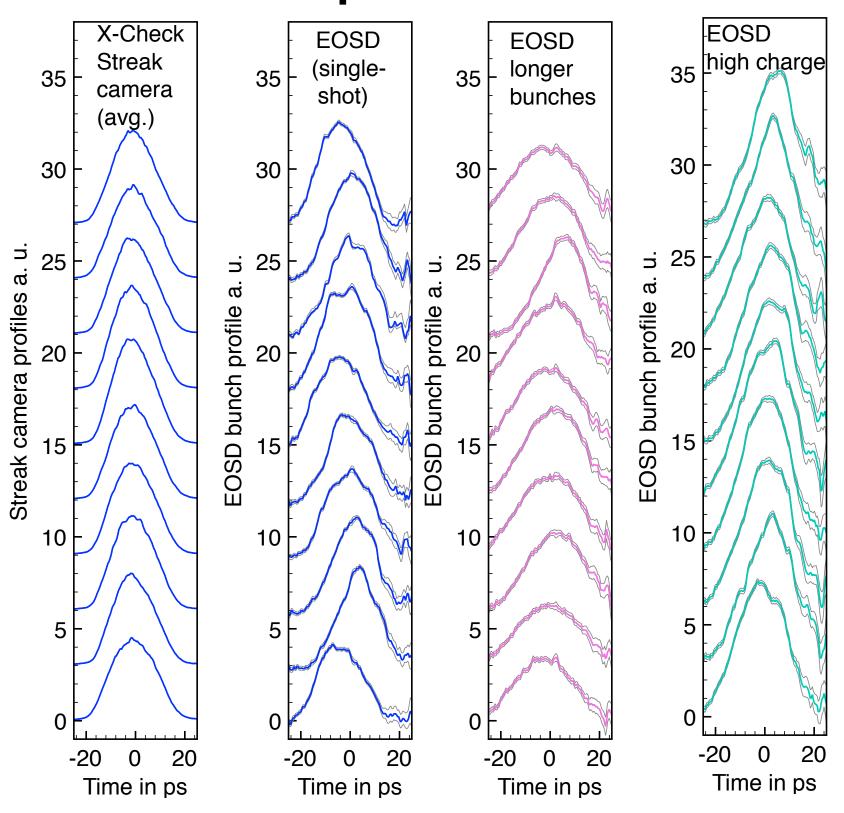
EOSD: Single-Shots - Sensitivity





EOSD: Single-shot bunch profiles for different electron beam parameters





Thank you for your attention/support!

